	arch N	

Application/Control No.	Applicant(s)/Patent under Reexamination
10/605,202	BAXTER, JOHN F.
Examiner	Art Unit
Zhiyu Lu	2618

	SEARCHED		
Class	Subclass	Date	Examiner
455	3.01 3.02 426 427	7/22/2005	ZL
455		7/22/2005	ZL
Updated	search	2/24/2006	ZL

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	

SEARCH NO (INCLUDING SEARCI)
	DATE	EXMR
Inventorship search	7/21/2005	ZL
Consulted with Lee Nguyen	7/21/2005	ZL
Consulted with Rafael Perez	7/25/2005	ZL
Updated search with keywords	2/24/2006	ZL